

Form 1449 (Modified) Information Disclosure Statement By Applicant (Use Several Sheets if Necessary)	Atty Docket No. LAM1P175/P1148	Application No.: Filed Herewith
	Applicant: KEIL et al. Filing Date Herewith	Group Unassigned

U.S. Patent Documents

Examiner Initial	No.	Patent No.	Date	Patentee	Class	Sub-class	Filing Date
EF	A	6,019,060	02/01/00	Lenz	118	723 R	06/24/98
EF	B	6,074,518	06/13/00	Imafuku et al.	156	345	01/04/99
EF	C	6,085,688	07/11/00	Lymberopoulos et al.	118	723 I	03/27/98
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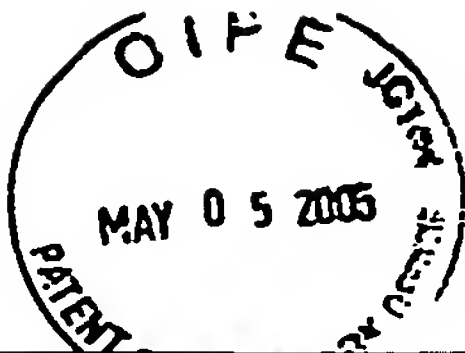
Foreign Patent or Published Foreign Patent Application

Examiner Initial	No.	Document No.	Publication Date	Country or Patent Office	Class	Sub-class	Translation	
							Yes	No
	J							
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Other Documents

Examiner Initial	No.	Author, Title, Date, Place (e.g. Journal) of Publication
	O	
	P	
	Q	
Examiner /Eric Fuller/		Date Considered 06/24/2006

Examiner: Initial citation considered. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.



Form 1449 (Modified) Information Disclosure Statement By Applicant (Use Several Sheets if Necessary)	Atty Docket No. LAM1P175/P1148	Application No.: 10/600,191
	Applicant: KEIL et al. Filing Date June 20, 2003	Group 1762

U.S. Patent Documents

Examiner Initial	No.	Patent No.	Date	Patentee	Class	Sub-class	Filing Date
EF	A	6,019,060	02/01/00	Lenz			06/24/98
EF	B	2003/0010454A	01/16/03	Bailey, III et al.			03/27/00
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Foreign Patent or Published Foreign Patent Application

Examiner Initial	No.	Document No.	Publication Date	Country or Patent Office	Class	Sub-class	Translation	
							Yes	No
	J							
	K							
	L							
	M							
	N							

Other Documents

Examiner Initial	No.	Author, Title, Date, Place (e.g. Journal) of Publication
EF	O	International Search Report, dated February 8, 2005
	P	
	Q	
Examiner /Eric Fuller/		Date Considered /Eric Fuller/

Examiner: Initial citation considered. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.